

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner Thien F Tran	Art Unit 2811	Page 1 of 1

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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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